# VALVE RLECTRONIC CV3986

SPECIFICATION MOSA/CV.3986 incorporat MI ISSUE NO. 1 DATED 15.5.57 To be read in conjunction with K.1006	SPECIFICATI		URITY VA	LVE			
TYPE OF VALVE - Subminiature Double with flying leads.  CATHODE - Indirectly heated.  ENVELOPE - Glass.  PROTOTYPE - 6021.	MARKING See K.1001/4. Additional Marking 6021						
RATING (All limiting values are absolute	<u>Base</u> Bs. 448/B8D/ <b>P</b>						
Heater Volts Heater Current Max. Operating Anode Voltage Max. Anode Dissipation Max. Negative Grid Voltage Max. Peak Anode Current Max. Peak Grid Current Max. Heater-Cathode Voltage Max. Bulb Temperature  (V) Max. Bulb Temperature	6.3 300 165 0.7 55 22 5.5 200 220	A A A	1 2 3 4	A G	node (2) rid (2) eater athode (athode (	a" g" h 2) k"	
Typical Operating Conditions Note A.  Anode Voltage (V) Anode Current (mA) Mutual Conductance (mA/V)	100 6.5		5 7 8	Heater Grid (1) Anode (1)		h g' a'	
Amplification Factor	5•4 <b>3</b> 5		Dimension		Min.	Max.	
Capacitances (pF) Cag (nom.) Cin (nom.)	1.5 2.4	A,B A,B	"A" Seated Height (m	·	9.3	34.92 10.16	
Cout (section 1) (nom.) Cout (section 2) (nom.) Ca! a" (max.) Cg! g" (max.)	0.28 0.32 0.52 0.013	B B B					
NOTES  A. Each section.  B. Without screen.							

Z.14492.R.

### INDIVIDUAL MILITARY SPECIFICATION SHEET

### ELECTRON TUBE, RECEIVING, TWIN TRIODE, SUBMINIATURE

JAN-6021

This specification short forms a part of the latest issue of Military Specification Mil-3-1.

Gathodo: Gosted Unipotential
Beso: Subministure - 8 Pin with long leads

pers: Smeathfature - 2 his airs load leads

Pin Ho.: 1 2 3 4 5 6 7 8 Element: 2p 2g h 2k lk h 1g lp Bieneter: 0.400 in. max. Height: 1.375 in. max.

Envelope: T-3

	llameone requirements. see Pa	regreph 3.3. Inspection in	etructic		lectron	Tubes							4
Bef.	Test	Conditions	MT(2)	Insp. Level or Gode	Syn.			Lin	lta .			Units	
						Min.	LAL	Bogle		Max.	ALD.		
	Smallfiestion Ameroral Test	)											
3.1	Qualification Approvals	Required for JAW Marking			-			Ì		l			
	Gathodes	Coated Unipotential				•							
3.4.3	Base Compections:												
	-Bessurements Accordance Tes	te Part 1. Note 3											
4.10.8	Heater Ourrent:	Note 4			If:		268	300	312		24	=4	-
4.30.8	Heater Ourrent:		0.65	11	If:	280				320		=4	l
4.10.15	Seater-Cathodo Leakage:	Note 23 New-/1007dc Enk1007dc	0.65	11	Ibks Ibks		=	=		5.0 5.0	<u></u>	nAde nAde	
4.30.6.1	Grid Corrects	Rh=150VdejRk=300; Rg=1.(MegjHote 23	0.65	п	les	•	-			-0.3		uade	
4.10.4.1	Plate Current(1):	Hotes 4, 23			Ibs		5.6	6.5	7.3		2.3	méde	-
4.30.4.1	Plate Current(1):		0.65	n	Ibs	4.5				8.5		nAde	
4.10.4.1	Plate Current(2):	lote 23	0.65	п	Ibi					200	-	uAdc	
4.30.9	Transcondustance(1):	Botes 4, 23			Sms		5000	5400	5800		3300	webce	-
4.30.9	Transconductance(1):		0.65	11	Sent	4450		-		6350		umbos	
4.7.5	Continuity and Shorte; (Insperatives)	;	0.4	п				-					
4.9.1	Hochenicals	Envelope (8-1)	-			-							
	Manuscramente Acceptance Zegi	e Part 2											
4.8.2	Insulation of Electrodess	Note 23 (g-all) (p-all)	2.5	1	R:	100		_		_		Hog Hog	

Ref.	Test	Conditions	ant(x)	Insp. Level or	Sys.	Min.	LAL	Limit: Bogie		Max.	1120	Units	
	M		+	Code	<del>                                     </del>	<del> </del> -			-	╁─╌	├	+	1
4.10.4.1	Plate Current(1) Difference					l				ļ.,			
4.10.4.1	Between Sections:	•	2.5	1	Ibs					1.6		BAdo	ŀ
4.10.9	Transconductance(2):	Ef=5.7V;Notes 22, 23	2.5	1	△왈'					15		×	ı
4.10.6.2	Grid Emissions	Ef=7.5V;Re=-7.5Vde; Eb=150Vde;Rk=0;Rg= 1.0Meg;Notes 23,24	2.5	1	Ios	0				-0.5		uAde	-
<b>4.10.3.</b> 2	AP Noise:	Esig=65mVac;Rg=0.lMeg; Rp=.0lMeg;Rk=75;Gk= 1000uf; Note 26	2.5	1	EB:					17		¥0	
	Pulse Emission:	Ef=6.0V; e pulse=50v; tp=25usec; prr=200pps Notes 23, 25	6.5	14	181	300						==	
.10.11.1	Amplification Factors	Note 23	6.5	14	Mus	30		35		40		ì	-
4.10.14	Gapacitance	No Shield; Note 23 No Shield; Note 23 No Shield; Section 1 No Shield; Section 2 No Shield No Shield	6.5	Gode F	Cgp: Cin: Cout: Cout: Cgg: Cpp:	1.2 1.8 0.20 0.22				1.8 3.0 0.36 0.42 0.013 0.52		unf unf unf unf unf unf	
	Low Pressure Voltage Breakdown:	Pressure=55f5mm Hg; Woltage=300Vac; Note 6	6.5	Note 5			-					:	
.9.20.3	Vibration(1):	No voltages; Post Shock and Fatigue Test End Points apply	10.0	Note 5									
.9.19.1	Vibration(2):	Rp=10000;Gk=1000af; F=40ops;G=15;Notes 7, 23	2,5	I	Eps					50		alf a.c	-
	Degradation Rate Accentance	Tests Note 8											
.9.5.3	Subminiature Lead Fatigue:	Note 9	2.5	Gode F		4						arcs	
.9.20.5	Shooks	Hammer angle=30°; Ehk=/100Vdc;Rg=0.lMeg; Note 10	20										
.9.20.6	Patigue:	G=2.5;Fixed frequency; F=25 min, 60 max.	6.5	Note 5				-		-			
_	Post Shock and Fatigue Test End Points:	Vibration(2) Heater-Cathode Leakage Ehk=/100Vdc			Ep:				_	200 20		mVac nAde	
		Ehk-loodd Change in Transconduc- tance(1) of individual tubes			Ihk: △Sp:			==		20 20		uAdo \$	
	Glass Strain:	Note 11	6.5	1		_							ļ .
Ref.	Test	Conditions	AGE(%)	Insp. Level		able De	r	1					
				Code	Che lst Samol	recter	etic Combine Sample	od Syn	144	inite . Mar	ί,	Units	
	Acceptance Life Tests Note	<del></del>				٦,		- 1	1	T			
.11.7	Heater Cycling Life Tests	Ef=7.0V; 1 min. on, 4 min. off; Ehk=140Vac; Eo=Eb=0;Hote 12	2.5	Gode H						.	.		
	Stability Life Test; (1 hour):	Ehk=/2007dc;Rg/g=1.0Meg; TA=Room;Notes 13, 26	1.0	Code I	,						.		
.11.4	Stability Life Test End Points:	Change in Transcon- ductance(1) of individual tubes						Δ8₹		1.5	,	۶	

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Ref.	Test	Conditions	AQL(%)	Insp. Level or Code		e Defectives per teristic Combined	Sym.	Lings Min.	18	Unite
				Code	Sample	Samples				
	Acceptance Life Tests Note	8(Contd)								
<b></b>	Survival Rate Life Test:	Stability Life Test Conditions or equi- valent; TA=Room; Notes 1h, 15	_	11		<del></del>		_	_	
4,11,4	Survival Rate Life Test	Continuity and Shorts	0.65	<b>—</b>		-			_	
	End Points:	(Inoperatives) Transconductance(1)	1.0	_		_	Smax	7000	_	wahos
រុវាខ	Intermittent Life Test:	Stability Life Test Conditions; TEnvelope= \$220°C min; Notes 16,17; 1000 Hour Requirements do not apply	·	_	1 .	<del></del> .		-		
14-11-14	Intermittent Life Test End Points; (500 Hours):	Note 18 Inoperatives; Note 19			1	3		_	_	
:	Note 16	Orid Current Heater Current	_	<u> </u>	1 2	3 3 5	Ic: If:	0 276	-0.9 328	υλdc ≡λ
		Change in Transconduc- tance(1) of individual	_	_	1	3	Δ ξ==	-	25	*
		Transconductance(2)	-	—	2	5	∆ <sup>Sm</sup> .	_	15	*
		Heater-Cathode Leakage Ehk-100Vdc Ehk-100Vdc	-	_	2	5	Ihka Ihka	=	10 10	nAdc nAdc
		Insulation of Electrodes g-all	l _	<b> </b>	2	5	R:	50 50	_	Meg Meg
		p-ell Transconductance(l) average change	_	_	_		VA8 ♥ Šω'	~	15	308
	÷	Total Defectives	_	_	4	8		_	_	
4,11,5	Information Life Test: (1000 Hours)	Intermittent Life Test Conditions;Notes 17,20, 21		<u> </u>						
	Packaging Information									
4.9.18.1.1	Carton Drops	(d) Package Group 1; Carton Size C								

Caution to Electron Equipment Design Engineers. Special attention should be given to the temperature at which the tubes are to be operated. Reliability will be seriously impaired if maximum envelope temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the tube and will be reduced appreciably if absolute maximum ratings are exceeded. Both reliability and performance will be jeopardised if filament voltage ratings are exceeded. Life and reliability of performance are directly related to the degree that regulation of the heater voltage is maintained at its center rated value.

- Note 1: The reference point for heater-cathode potential shall be the positive terminal of the cathode resistor, unless other-wise specified.
- Note 2: If altitude rating is exceeded, reduction of instantaneous voltages (Ef, excluded) may be required.
- Hote 3: The AQL for the combined defectives for attributes in Measurements Acceptance Tests, Part 1, excluding Inoperatives and Mechanical shall be one (1) percent. A tube having one (1) or more defects shall be counted as one (1) defective. MIL-STD-105, Inspection Level II shall apply.
- Note h: Variables Sampling Procedure:

### Test for Lot-Average Acceptance:

Select a 35 tube sample at random from the lot. Number these tubes consecutively.

Determine the numerical average value of the characteristic specified on the specification sheet of the 35 tube sample. If this value is on or above the IAL and on or below the UAL, accept for Lot Average.

Note 4: (Contd)

Please for Lot Dispersion Acceptance:

Divide the 35 tube sample into seven (7) consecutive sub-groups of five (5) tubes each. Determine the range, R, of each sub-group for the measured characteristic specified on the Specification Sheet.

Gospute the numerical average of the R values which is equal to R. If R is equal to or less than the ALD, accept for Lot Dispersion.

- Hote 5: This test shall be conducted on the initial lot and thereafter on a lot approximately every 30 days. Once a lot has passed, the 30-day rule shall apply. In the event of lot failure, the lot shall be rejected and the succeeding lot shall be subjected to this test. HII-STD-105, sample size code letter F shall apply.
- Note 6: There shall be no evidence of arcing or corona between anode pins and adjacent pins with no other voltages applied.
- Note 7: For wibration tests, the impedance of the plate voltage supply shall not exceed that of a 40 uf capacitor at 10cps.
- Mote &: Destructive tests:

s subjected to the following destructive tests are not to be accepted under this specification.

- 4.9.5.3 Subminiature Lead Fatigue 4.9.20.5 Shock. 4.9.20.6 Fatigue. 4.11.7 Heater Oycling Life Test. 4.11.5 Intermittent Life Test.
- When a manufacturer submits tubes for qualification approval, five extra tubes shall be submitted for lead fatigue testing. These may be electrical rejects.
- Note 10: Leads may be elipped for application of voltages during impact.
- Note 11: Glass strain procedures All tubes submitted to this shall have been scaled a minimum of 48 hours prior to conducting this test. All tubes shall be at room temperature. The entire tube shall be immored in water not less than 85°0 for 15 seconds and immediately thereafter immersed in water not more than 5°0, for 5 seconds. The volume of water shall be large enough that the temperature will not be appreciably affected by the test. The method of submersion shall be in accordance with Drawing \$245-JaN, and such that a minimum of heat is conducted eavy by the holder used. The tubes shall be placed in the water so that no contact is made with the containing wessel, nor shall the tubes contact each other. After the 5-second submersion period, the tubes shall be removed and allowed to dry at room temperature on a wooden surface. After drying at room temperature for a period of 48 hours, the tubes shall be impected and rejected for evidence of air leaks. Electrical rejects other than imperatives may be used in the performance of this test.
- Note 12: The regulation of the heater voltage supply shall be not more than 3.0 percent. This test shall be made on a lot by lot basis. A failure or defect shall consist of an open heater, open cathode circuit, or a heater-eathode short.
- Note 13: Stability Life Test:
  - a. Life test samples shall be selected from a lot at random in such a manner as to be representative of the lot. I such selection results in a sample containing tubes which are outside the initial specification sheet limits for the relevant life test end point characteristics, such tubes shall be replaced by randomly selected acceptable.
  - b. Serially mark all tubes from the sample.
  - Record referenced characteristic measurements after a maximum operation of 15 minutes at specified voltage and current conditions on the entire sample.
  - d. Operate at life test conditions for one (1) hour (plus 30 minutes, minus 0 minutes). Life test shall be conducted as pur paragraphs 4.11 and 4.11.7, MIL-2-1, except that the following shall be substituted for the third sentence of 4.11: The mean electrode potentials, except heater or filament, may be established at values differing by not more than % from the specified values provided the same average electrode dissipations are obtained that occur with the specified voltages. Fluctuations of all voltages including heater or filament voltage shall be as small as practical.
  - Assert referenced characteristic measurements at the end of this test period. Referenced characteristic measurements shall be taken immediately following the test or tubes shall be prehented 15 minutes, under specified test voltage and current conditions, and immediately measured. The 15 minutes preheat shall be considered as part of the test time.
  - f. A defective shall be defined as a tube having a change in referenced characteristic greater than that specified on the specification sheet.
  - g. A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection, Vibration, and Low Pressure Voltage Breakdown tests.
- Hote 14: HEANS OF ASSIBITED SURVIVAL RATE. The procedure for assuring the maintenance of a desirable quality level in terms of early life survival consists of a series of normal, reduced, and tightened inspection plans for use at 100 hours. The sample size is dependent upon lot size, and the transfer between normal, reduced, and tightened inspection is dependent upon quality history.

The selection of inspection scheme and sampling plan shall be in accordance with Inspection Instructions for Electron Tubes paragraph 5,3.4.2 through 5.3.4.3.1.3 inclusive except that paragraph 5,3.4.2.2 shall be modified by deleting the last part of the first sentence which states ".... or if no lot in the last 20 lots inspected shall have been declared non-conforming for life test qualities." At the zamufacturer's option, reduced inspection may be used if no lot in the last ten (10) lots inspected shall have been declared non-conforming.

#### Note 14: (Comtd)

#### INSPECTION PROCEDURE

- a. Select sample in accordance with Note 13, paragraph (a).
- b. Tubes to be tested at 100 hours as provided in MIL-E-1(4.7.5). When any tap-short indication is obtained, the test shall be repeated. When any short indication is again obtained the tube will be rejected as an incorrative.
- c. Determine the number of defective tubes at the 100 hour period.
- d. If more than the allowable number of defectives occur, declare the lot non-conforming.
- e. A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection, Vibration, and Low Pressure Voltage Breakdown tests.
- Hote 15: For Survival Rate Life Test, the equivalent Stability Life Test conditions shall be interpreted as having the same heater voltage (Ef) and heater-cathode voltage (Eth) as the Stability Life Test; and the same interruptions of MIL-E-1 paragraph 4.11.5 as the Intermittent Life Test. The electrode voltages shall be such that the element dissipations are not less than 80 percent, nor more than 100 percent of Stability Life Test Plate Dissipation. These voltages are to be maintained within the limits of plus 200, minus 50 percent of the Stability Life Test voltages.

#### Note 16: Intermittent Life Tests:

- a. The first 20 tubes of the Stability Life Test sample which meet the measurements acceptance test limits for those characteristics specified as Intermittent Life Test End Points shall be used for the Intermittent Life Test sample. In the event that a second Stability Life Test sample is used, the first 20 tubes from that sample which meet the above conditions shall be used.
- b. In the event of failure of the first sample on Intermittent Life Test, take a completely fresh sample (MIL-STD-105 sample size code letter I) and stabilize it in accordance with the conditions of the Stability Life Test. Then select from it the first 40 tubes which meet the measurements acceptance test limits for those characteristics specified as Intermittent Life Test End Founts.

  Subject these 40 tubes to the Intermittent Life Test. Acceptance shall then be based on combined results from the first and second samples.
- c. As an alternate method, the manufacturer may select his life test sample as described in Note 13, paragraph (a).
- d. Life test shall be conducted as per paragraphs 4.11, and 4.11.5, MIL-E-1, except that the following shall be substituted for the third sentence of 4.11: The mean electrode potentials, except heater or filament may be established at values differing by not more than 5% from the specified values provided the same average electrode dissipations are obtained that occur with the specified voltages. Finatuations of all voltages including heater or filament voltage shall be as small as practical.
- e. Regular Life Test
  - 1. Regular Life test shall be conducted for 1000 hours.
  - Regular life test acceptance shall be on the basis of the 500 and 1000 hours requirements as indicated on Specification Sheet.
  - Regular life test shall be in effect initially and shall continue in effect until the eligibility criteria for the Reduced Hours Life Test have been met.
- f. Reduced Hours Life Test:
  - Reduced Hours Life Test shall be conducted for 500 hours and acceptance shall be based on the 500 hour end point limits.
  - Slightlity for Reduced Hours Life Tests: No lot failure due to the 1000 hour life test has occurred
    in the preceding three (3) consecutive lots.
  - Loss of eligibility for Reduced Hours Life Test: Two (2) or more 500 hour life test lot failures
    occurring in the last three (3) consecutive lots.
- g. The life test sample shall be read at the following times:

O hours 500 hours (plus 48 hours; minus 24 hours) 1000 hours (plus 48 hours; minus 24 hours; mhen in force)

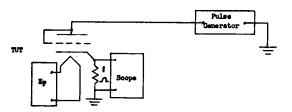
Additional reading periods may be used at the discretion of the electron tube manufacturer.

#### Note 16: (Comtd)

- h. Acceptance Criteria: The lot shall be considered satisfactory for acceptance provided that the specified allowable defects are not exceeded and the change of the average of any characteristic in the life test sample specified for life test control of everage is not exceeded. The average percentage change shall be ascertained from the determination of the individual changes for each tube in the life test sample from the sero (o) hour value for the referenced characteristic or characteristics. For purposes of computation of this average percentage change, the absolute values of the individual changes for each tube in the life test sample shall be used. Any tube found inoperative during life testing shall not be considered in the calculation of this average.
- A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection, Vibration, and Low Pressure Voltage Breakdoms.
- j. Not more than one (1) accidental breakage shall be allowed in the life test sample. In the event that one (1) life test tube is accidentally broken, acceptability of the life test sample shall be based upon the remaining tubes in the sample provided that the broken tube was not known to be a defective.
- Note 17: Envelope Temperature is defined as the highest temperature indicated when using a thermocouple of #40 BS or smaller diameter elements welded to a ring of .025 inch diameter phosphor bronze placed in contact with the envelope.
- Note 18: Order for evaluation of life test defects. If a tube is defective for more than one attribute characteristic, the characteristic appearing first in the life test end points shall constitute the failure.
- Hote 19s An inoperative as referenced in Life Test is defined as a tube having one (1) or more of the following defects: discontinuity (Ref. MIL-E-1, par. 4.7.1), shorts (Ref. MIL-E-1 par. 4.7.2) air leaks.
- Hote 20: On Information Life Tests, read same characteristics as Intermittent Life Test. Limits do not apply. Six copies of these data shall be forwarded to the Armed Services Electron Tube Committee upon request.
- Hote 21: This life test shall be conducted on a minimum of one sample of ten tubes each month of production. This sample shall be selected as the first ten serially marked, noninoperative tubes from a completed intermittent life Test sample. This life test shall be classified as a destructive test. Read at 1000 hours.
- Note 22: Transconductance(2) is the percent change in Transconductance(1) of an individual tube resulting from the change in Rf.
- Note 23: Test each section separately.
- Hote 24s Prior to this test tubes shall be preheated 5 minutes with both sections operating separately at conditions indicated below. Test within three (3) seconds after preheating. Three-minute test is not permitted. Grid Emission shall be the last test performed on the sample selected for the Grid Emission test.

Ef	Ec.	Eb	Rk	Rg
٧	Vde	Vde	ohns	Meg
7.5	0	150	500	1.0

Hote 25: The pulse is essentially a square wave with 1.0 used rise time and 0.8 used fall. The pulse shall be applied to plate and grid tied together. Pulse emission shall be measured in terms of voltage developed across a 1.0 one resistor in the cathode circuit. Test limit as measured by the leading edge of a calibrated trace, the amplitude of the trailing edge of which shall not vary by more than 20 percent from the value of the leading edge. Test each unit separately.



- Note 26: Tie lk to 2k; lg to 2g; and lp to 2p.
- Note 27: Reference specification shall be of the issue in effect on the date of invitation for bid.